

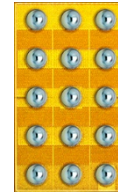
EPC2045 – Enhancement-Mode Power Transistor Preliminary Specification Sheet



Status: Engineering

Features:

- V_{DS} , 100 V
- Maximum $R_{DS(on)}$, 7 m Ω
- I_D , 16 A



Applications:

- Open Rack Server Architectures
- LiDAR/Pulsed Power Applications
- USB-C
- Isolated Power Supplies
- Point of Load Converters
- Class D Audio
- LED Lighting
- Low Inductance Motor Drive

EPC2045 eGaN[®] FETs are supplied in passivated die form with solder bumps.

Die Size: 2.5 mm x 1.5 mm

Maximum Ratings			
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5ms pulses at 150°C)	120	
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 38^\circ\text{C/W}$)	16	A
	Pulsed (25°C , $T_{PULSE} = 300 \mu\text{s}$)	130	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	°C
T_{STG}	Storage Temperature	-40 to 150	

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$, $I_D = 0.3\text{ mA}$	100			V
I_{DSS}	Drain Source Leakage	$V_{DS} = 80\text{ V}$, $V_{GS} = 0\text{ V}$		0.1	0.25	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$		1	5	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		0.1	0.25	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 5\text{ mA}$	0.8	1.5	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$, $I_D = 16\text{ A}$		5.6	7	m Ω
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5\text{ A}$, $V_{GS} = 0\text{ V}$		1.9		V

All measurements were done with substrate shorted to source.

Thermal Characteristics			
		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	8.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	64	°C/W

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

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Dynamic Characteristics (T _j = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance	V _{DS} = 50 V, V _{GS} = 0 V		570	685	pF
C _{RSS}	Reverse Transfer Capacitance			5		
C _{OSS}	Output Capacitance			260	390	
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (note 2)	V _{DS} = 0 to 50 V, V _{GS} = 0 V		320		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (note 3)			420		
R _G	Gate Resistance			0.6		Ω
Q _G	Total Gate Charge	V _{DS} = 50 V, V _{GS} = 5 V, I _D = 16 A		5.2	6.5	nC
Q _{GS}	Gate-to-Source Charge	V _{DS} = 50 V, I _D = 16 A		1.7		
Q _{GD}	Gate-to-Drain Charge			1.1		
Q _{G(TH)}	Gate Charge at Threshold			1.2		
Q _{OSS}	Output Charge	V _{DS} = 50 V, V _{GS} = 0 V		21	32	
Q _{RR}	Source-Drain Recovery Charge			0		

Note 2: C_{OSS(ER)} is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Note 3: C_{OSS(TR)} is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

All measurements were done with substrate shorted to source.

Figure 1: Typical Output Characteristics at 25°C

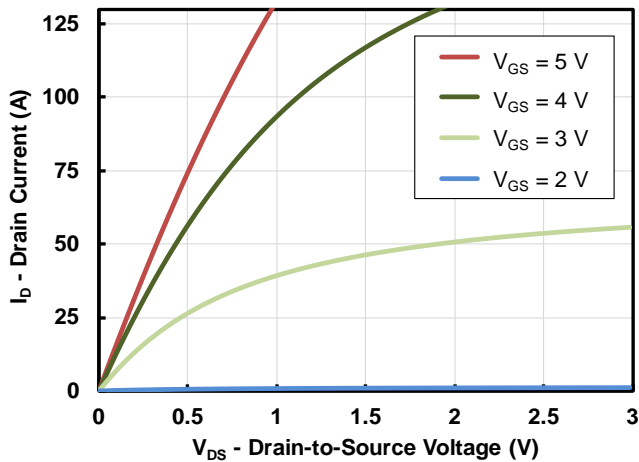
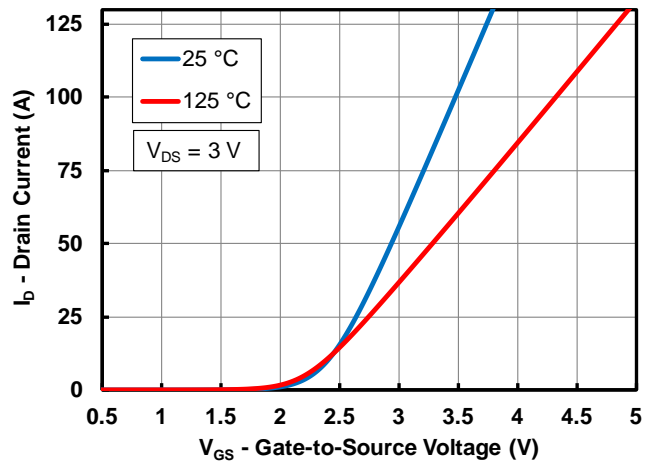


Figure 2: Transfer Characteristics



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Figure 3: $R_{DS(on)}$ vs V_{GS} for Various Drain Currents

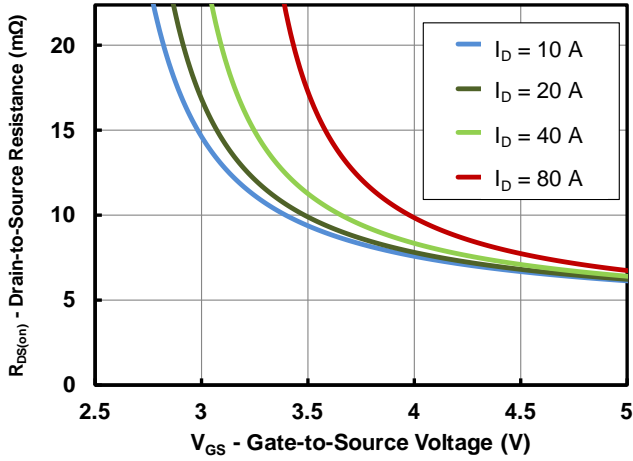


Figure 4: $R_{DS(on)}$ vs V_{GS} for Various Temperatures

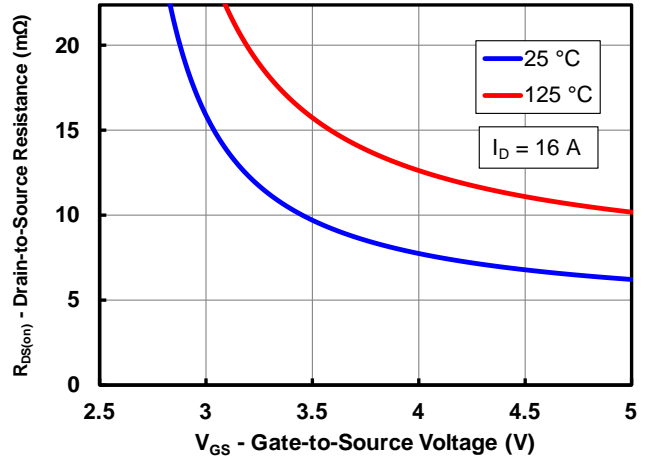


Figure 5a: Capacitance (Linear Scale)

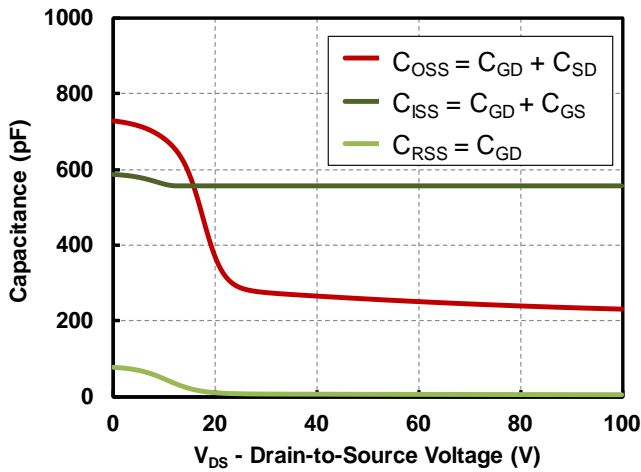


Figure 5b: Capacitance (Log Scale)

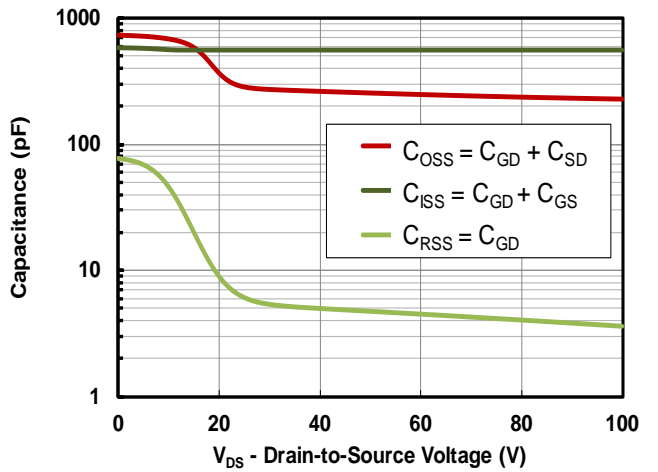


Figure 5c: Output Charge and C_{OSS} Stored Energy

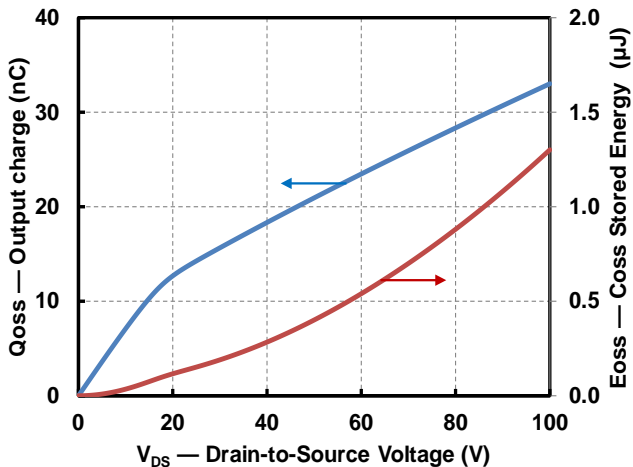
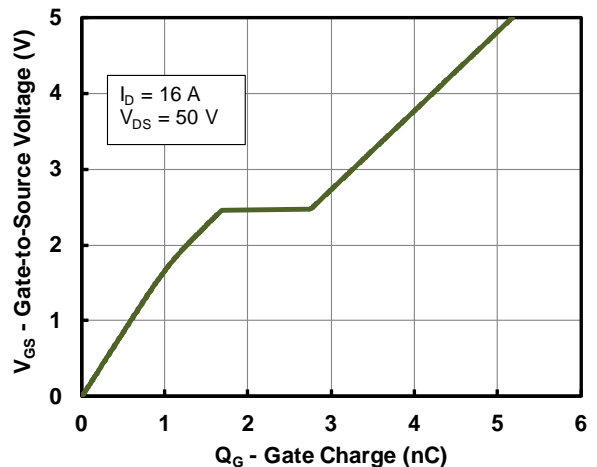


Figure 6: Gate Charge



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Figure 7: Reverse Drain-Source Characteristics

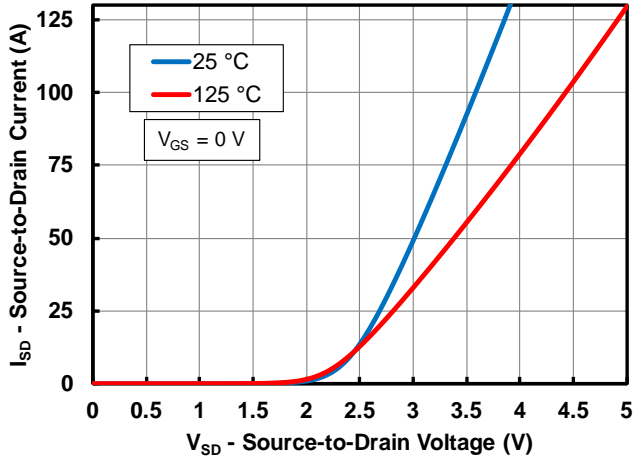


Figure 8: Normalized On-State Resistance vs Temperature

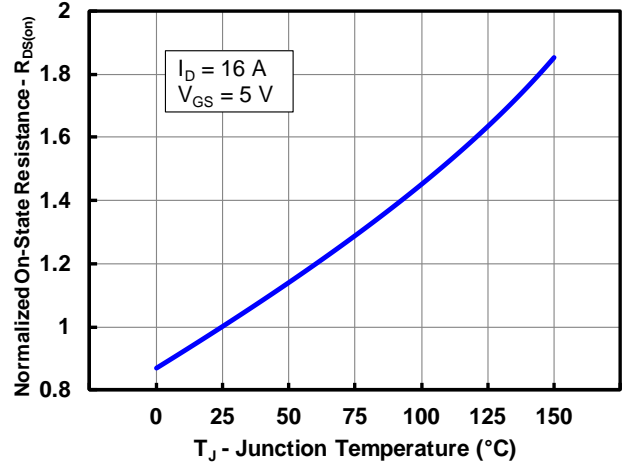


Figure 9: Normalized Threshold Voltage vs Temperature

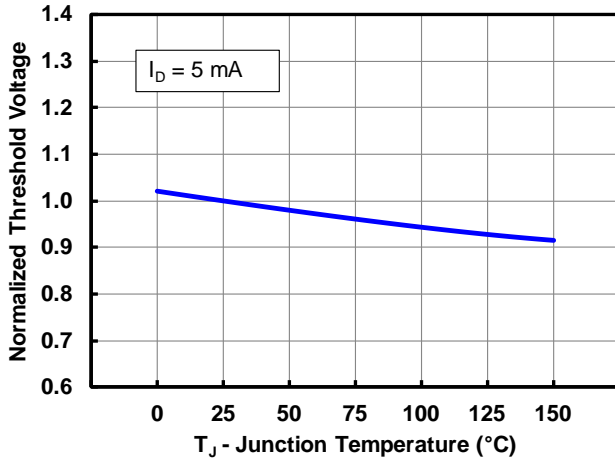
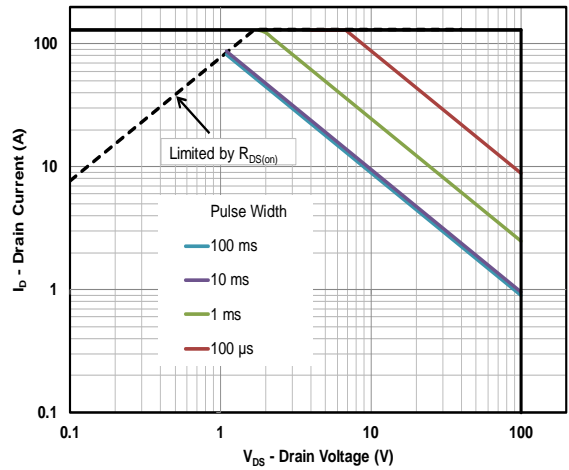


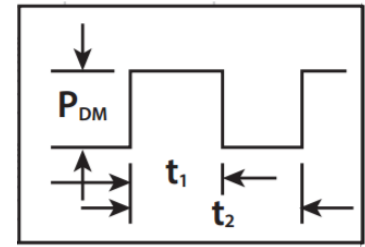
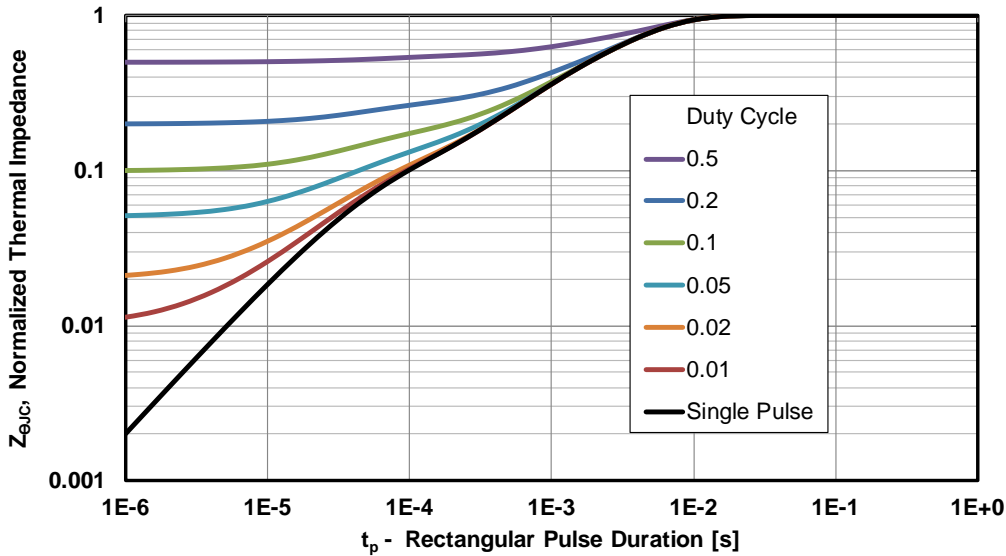
Figure 10: Safe Operating Area



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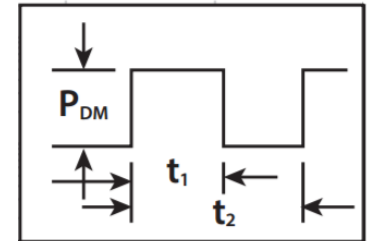
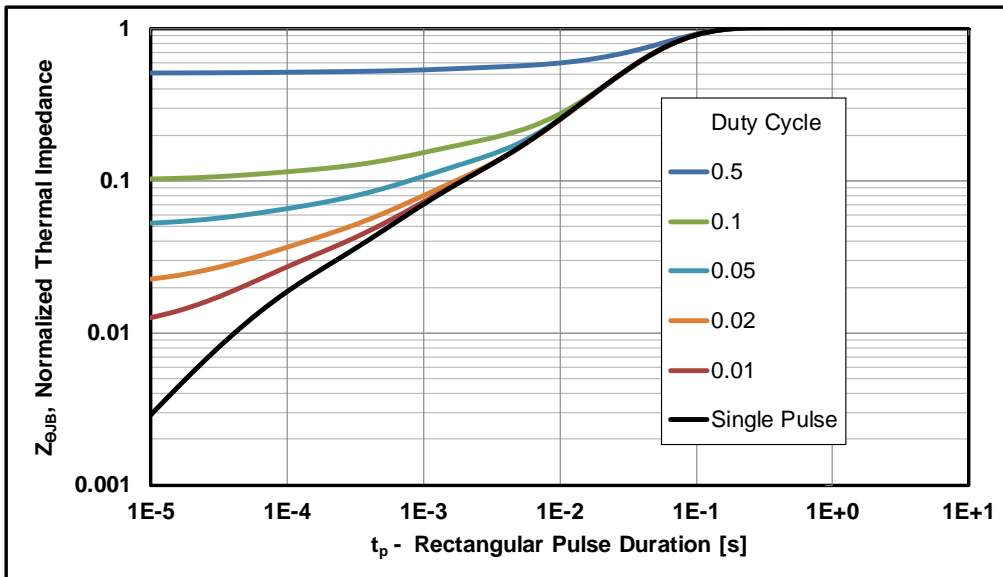


Figure 11a: Transient Thermal Response Curves (Junction-to-Case)



Notes:
 Duty Factor: $D = t_1/t_2$
 Peak $T_J = P_{DM} \times Z_{\theta JC} \times R_{\theta JC} + T_C$

Figure 11b: Transient Thermal Response Curves (Junction-to-Board)



Notes:
 Duty Factor: $D = t_1/t_2$
 Peak $T_J = P_{DM} \times Z_{\theta JB} \times R_{\theta JB} + T_B$

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DIE MARKINGS

2045
YYYY
ZZZZ

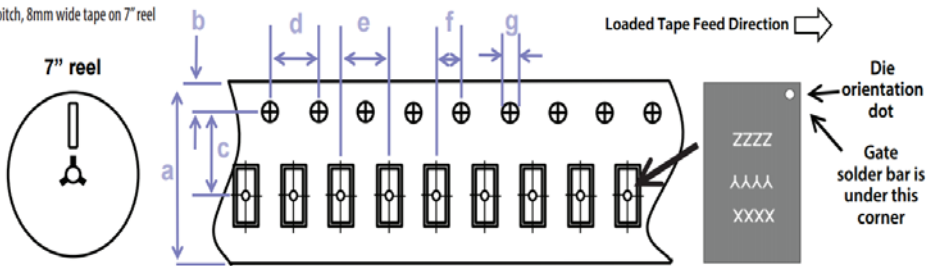
Part Number	Laser Marking		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2045ENGRT	2045	YYYY	ZZZZ

Die orientation dot → ●

Gate Pad bump is under this corner →

TAPE AND REEL CONFIGURATION

4mm pitch, 8mm wide tape on 7" reel



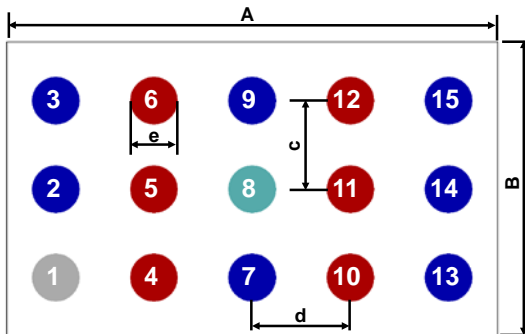
Dimension (mm)	EPC2045 (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Die is placed into pocket solder bar side down (face side down)

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

DIE OUTLINE

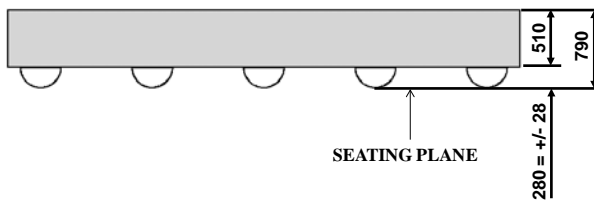
Solder Bar View



Pads 1 is Gate;
 Pads 2, 3, 7, 9, 13, 14, 15 are Source;
 Pads 4, 5, 6, 10, 11, 12 are Drain;
 Pad 8 is substrate

DIM	MICROMETERS		
	MIN	Nominal	MAX
A	2470	2500	2530
B	1470	1500	1530
c		450	
d		500	
e	238	264	290

Side View

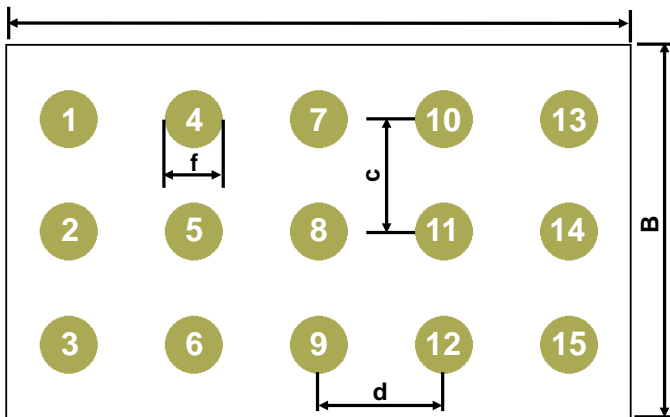


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RECOMMENDED LAND PATTERN

(measurements in μm)



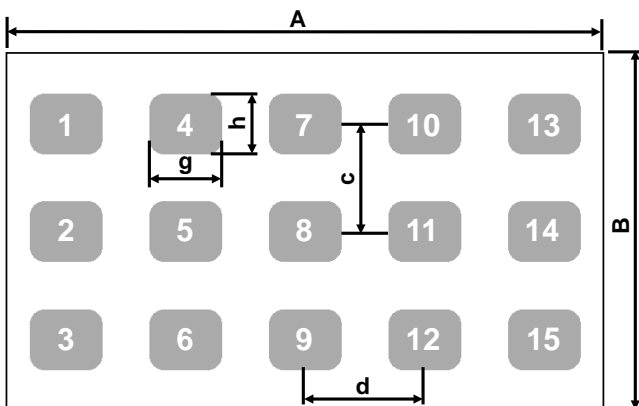
The land pattern is solder mask defined
Solder mask is $10\mu\text{m}$ smaller per side than bump

DIM	MICROMETERS
A	2500
B	1500
c	450
d	500
f	230

Pads 1 is Gate;
Pads 2, 3, 7, 9, 13, 14, 15 are Source;
Pads 4, 5, 6, 10, 11, 12 are Drain;
Pad 8 is substrate

RECOMMENDED STENCIL DRAWING

(measurements in μm)



DIM	MICROMETERS
A	2500
B	1500
c	450
d	500
g	300
h	250

Recommended stencil should be 4mil ($100\mu\text{m}$) thick, must be laser cut, openings per drawing.

The corner has a radius of R60

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at epc-co.com/epc/DesignSupport/AssemblyBasics.aspx

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